

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	10/017,021	YUTKOWITZ, STEPHEN J.	
	Examiner	Art Unit	Page 1 of 1
	Joshua C Liu	2121	

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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